Power MOSFET 60 V, 24 mΩ, 20 A, Single N–Channel

Features

- Small Footprint (3.3 x 3.3 mm) for Compact Design
- Low R_{DS(on)} to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- NV Prefix for Automotive and Other Applications Requiring AEC-Q101 Qualified Site and Change Controls
- These are Pb–Free Devices

MAXIMUM RATINGS (T_J = 25°C unless otherwise noted)

			,		
Parameter			Symbol	Value	Unit
Drain-to-Source Voltage			V _{DSS}	60	V
Gate-to-Source Voltage	e		V _{GS}	±20	V
Continuous Drain Cur-		T _{mb} = 25°C	۱ _D	20	А
rent R _{ΨJ-mb} (Notes 1, 2, 3, 4)	Steady	$T_{mb} = 100^{\circ}C$		14	
Power Dissipation	State	T _{mb} = 25°C	PD	22	W
R _{ΨJ-mb} (Notes 1, 2, 3)		$T_{mb} = 100^{\circ}C$		11	
Continuous Drain Cur-		$T_A = 25^{\circ}C$	۱ _D	7.6	А
rent R _{θJA} (Notes 1 & 3, 4)	Steady	$T_A = 100^{\circ}C$		5.4	
Power Dissipation	State	T _A = 25°C	PD	3.2	W
$R_{\theta JA}$ (Notes 1, 3)		T _A = 100°C		1.6	
Pulsed Drain Current	Pulsed Drain Current $T_A = 25^{\circ}C, t_p = 10 \ \mu s$			127	А
Operating Junction and Storage Temperature			T _J , T _{stg}	–55 to +175	°C
Source Current (Body Diode)			I _S	18	А
Single Pulse Drain-to-Source Avalanche Energy (T _J = 25°C, V _{DD} = 24 V, V _{GS} = 10 V, $I_{L(pk)} = 20 \text{ A}, L = 0.1 \text{ mH}, R_G = 25 \Omega$)			E _{AS}	20	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			ΤL	260	°C

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

THERMAL RESISTANCE MAXIMUM RATINGS (Note 1)

Parameter	Symbol	Value	Unit
Junction-to-Mounting Board (top) – Steady State (Note 2 and 3)	$R_{\PsiJ-mb}$	6.8	°C/W
Junction-to-Ambient - Steady State (Note 3)	$R_{\theta JA}$	47	

1. The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.

2. Psi (Ψ) is used as required per JESD51–12 for packages in which substantially less than 100% of the heat flows to single case surface.

3. Surface-mounted on FR4 board using a 650 mm², 2 oz. Cu pad.

4. Continuous DC current rating. Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.

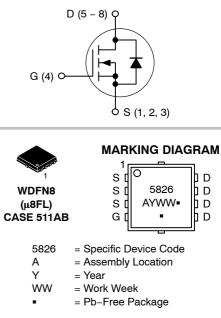


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V _{(BR)DSS}	R _{DS(on)} MAX	I _D MAX
60 V	24 mΩ @ 10 V	20 A
	$32 \mathrm{m}\Omega @ 4.5 \mathrm{V}$	207

N-Channel



(Note: Microdot may be in either location)

ORDERING INFORMATION

Device	Package	Shipping [†]
NVTFS5826NLTAG	WDFN8 (Pb-Free)	1500 / Tape & Reel
NVTFS5826NLTWG	WDFN8 (Pb-Free)	5000 / Tape & Reel

+For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

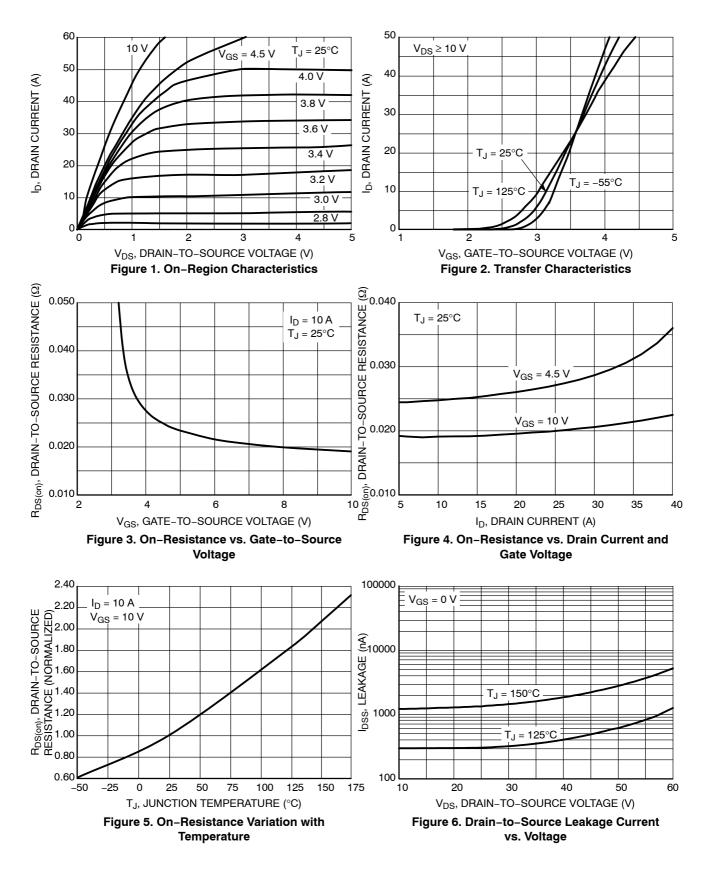
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ELECTRICAL CHARACTERISTICS (T_J = 25° C unless otherwise noted)

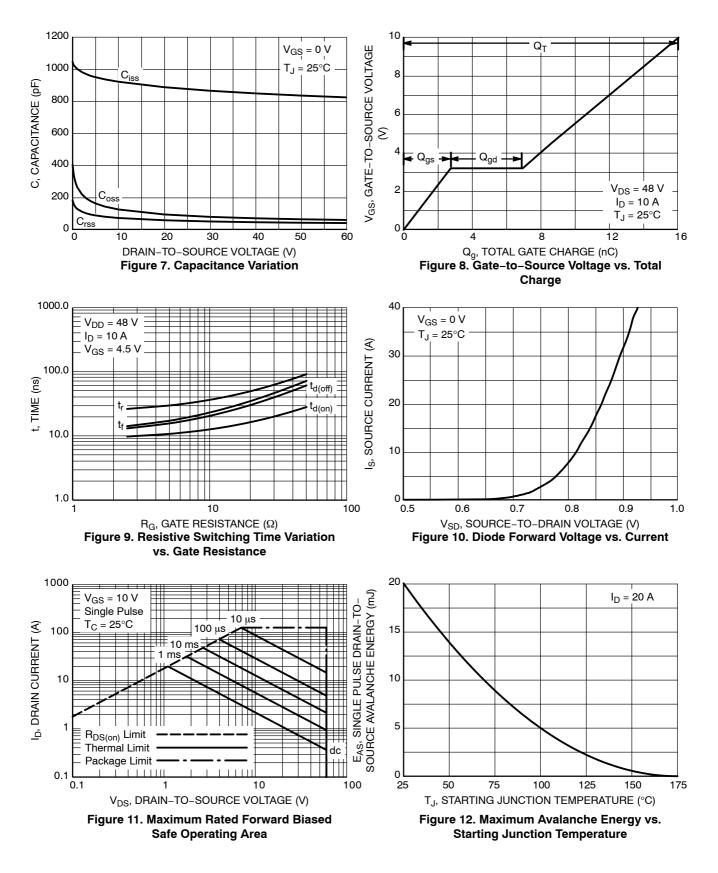
Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS					•		
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	V_{GS} = 0 V, I_D = 250 μ A		60			V
Zero Gate Voltage Drain Current	I _{DSS}	V _{GS} = 0 V, V _{DS} = 60 V	$T_J = 25^{\circ}C$			1.0	μA
			T _J = 125°C			10	
Gate-to-Source Leakage Current	I _{GSS}	$V_{DS} = 0 V, V_{GS}$	_S = ±20 V			±100	nA
ON CHARACTERISTICS (Note 5)							
Gate Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}, I_{D}$	= 250 μA	1.5		2.5	V
Drain-to-Source On Resistance	R _{DS(on)}	V _{GS} = 10 V, I	_D = 10 A		19	24	mΩ
		V _{GS} = 4.5 V,	I _D = 10 A		25	32	
Forward Transconductance	9 _{FS}	V _{DS} = 15 V,	I _D = 5 A		8		S
CHARGES AND CAPACITANCES							
Input Capacitance	C _{iss}	V _{GS} = 0 V, f =	1.0 MHz,		850		pF
Output Capacitance	C _{oss}	V _{DS} = 2	5 V		85		1
Reverse Transfer Capacitance	C _{rss}				50		
Total Gate Charge	Q _{G(TOT)}				8.3		nC
Threshold Gate Charge	Q _{G(TH)}				1		nC
Gate-to-Source Charge	Q _{GS}	V _{GS} = 4.5 V, V _{DS} =	48 V, I _D = 10 A		3		
Gate-to-Drain Charge	Q _{GD}				4		1
Total Gate Charge	Q _{G(TOT)}	V_{GS} = 10 V, V_{DS} = 48 V, I_{D} = 10 A			16		nC
SWITCHING CHARACTERISTICS (No	te 6)						
Turn-On Delay Time	t _{d(on)}				9		ns
Rise Time	t _r	V _{GS} = 4.5 V, V	_{DS} = 48 V,		29		
Turn-Off Delay Time	t _{d(off)}	V _{GS} = 4.5 V, V _I I _D = 10	A		14]
Fall Time	t _f	1			21]
DRAIN-SOURCE DIODE CHARACTER	ISTICS						
Forward Diode Voltage	V _{SD}	V _{GS} = 0 V, I _S = 10 A	$T_J = 25^{\circ}C$		0.8	1.2	V
			T _J = 125°C		0.7		7
Reverse Recovery Time	t _{RR}	V_{GS} = 0 V, dI_S/dt = 100 A/µs, I_S = 10 A			18		ns
Charge Time	t _a				14		
Discharge Time	t _b				4		
Reverse Recovery Charge	Q _{RR}				17		nC

Pulse Test: Pulse Width ≤ 300 μs, Duty Cycle ≤ 2%.
Switching characteristics are independent of operating junction temperatures.

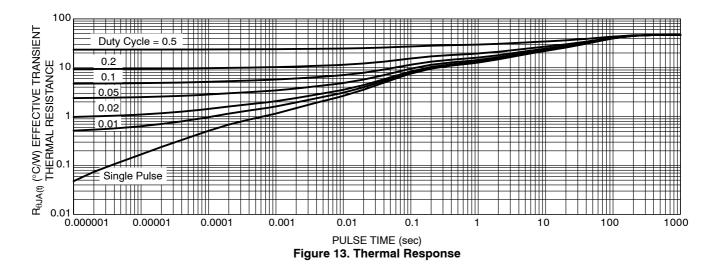
TYPICAL CHARACTERISTICS



TYPICAL CHARACTERISTICS

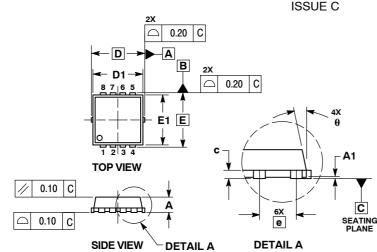


TYPICAL CHARACTERISTICS



PACKAGE DIMENSIONS

WDFN8 3.3x3.3, 0.65P CASE 511AB

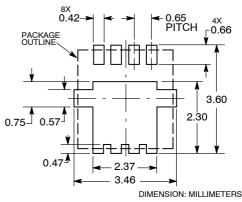


NOTES

- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994. CONTROLLING DIMENSION: MILLIMETERS. 1. 2.
- DIMENSION D1 AND E1 DO NOT INCLUDE MOLD FLASH PROTRUSIONS OR GATE BURRS. з

	MILLIMETERS			INCHES				
DIM	MIN	NOM	MAX	MIN	NOM	MAX		
Α	0.70	0.75	0.80	0.028	0.030	0.031		
A1	0.00		0.05	0.000		0.002		
b	0.23	0.30	0.40	0.009	0.012	0.016		
с	0.15	0.20	0.25	0.006	0.008	0.010		
D		3.30 BSC			0.130 BSC			
D1	2.95	3.05	3.15	0.116	0.120	0.124		
D2	1.98	2.11	2.24	0.078	0.083	0.088		
E	3.30 BSC			0.130 BSC				
E1	2.95	3.05	3.15	0.116	0.120	0.124		
E2	1.47	1.60	1.73	0.058	0.063	0.068		
E3	0.23	0.30	0.40	0.009	0.012	0.016		
е	0.65 BSC			0.026 BSC				
G	0.30	0.41	0.51	0.012	0.016	0.020		
ĸ	0.64			0.025				
L	0.30	0.43	0.56	0.012	0.017	0.022		
L1	0.06	0.13	0.20	0.002	0.005	0.008		
М	1.40	1.50	1.60	0.055	0.059	0.063		
θ	0°		12°	0°		12°		

SOLDERING FOOTPRINT*



*For additional information on our Pb -Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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